

Fig. 1



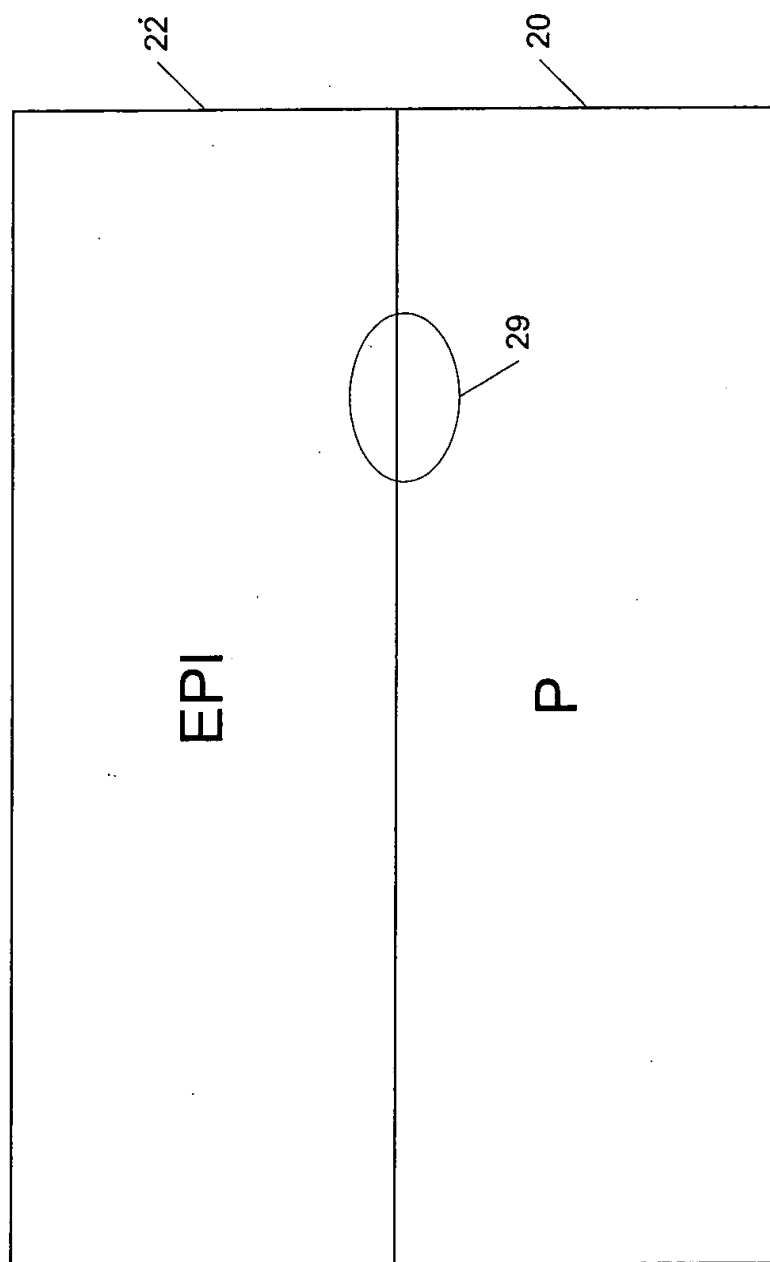
[illegible]

Fig. 2b

FIG. 2c is a cross-sectional view of the device of FIG. 2b, taken along line 2c-2c of FIG. 2b. The device includes a substrate 20, a P-type region 22, and an EPI layer 24. A gate stack 26 is formed on the EPI layer 24, and a source/drain region 28 is formed in the P-type region 22. A contact 29 is formed in the source/drain region 28.

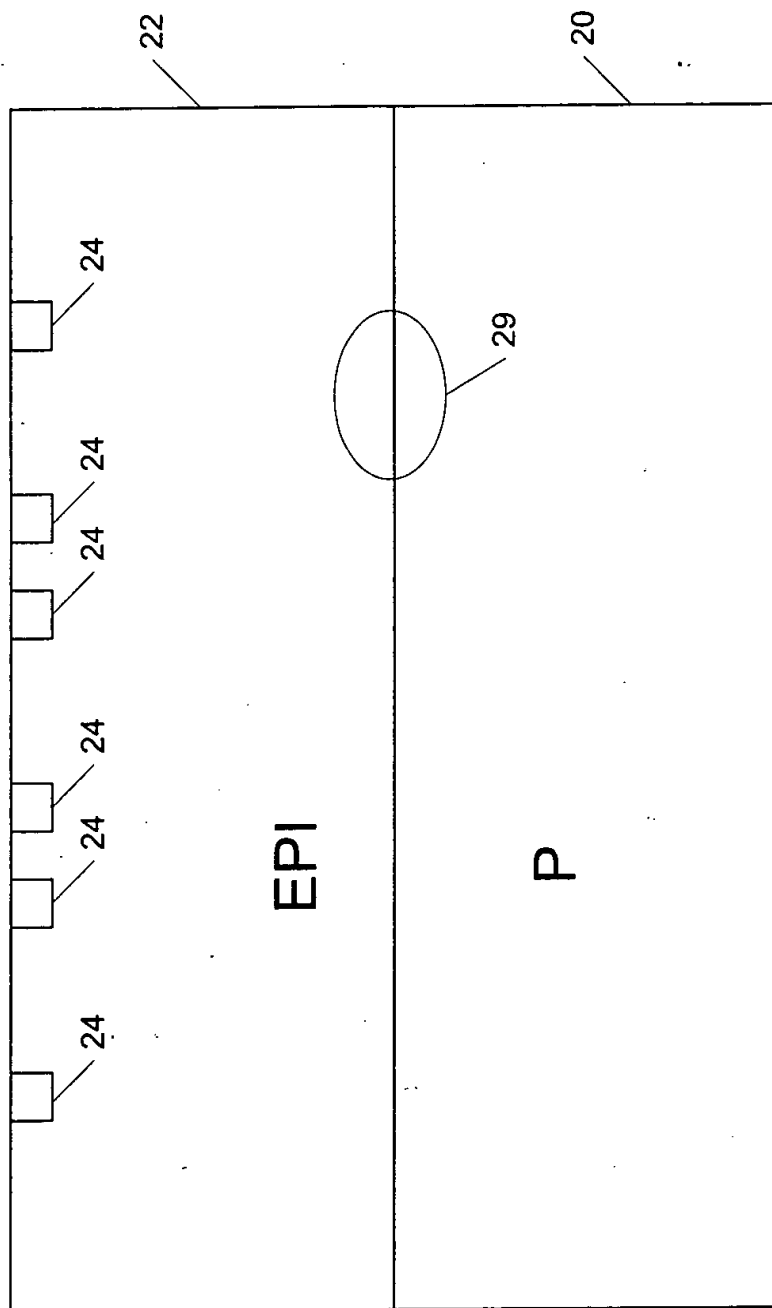


Fig. 2c

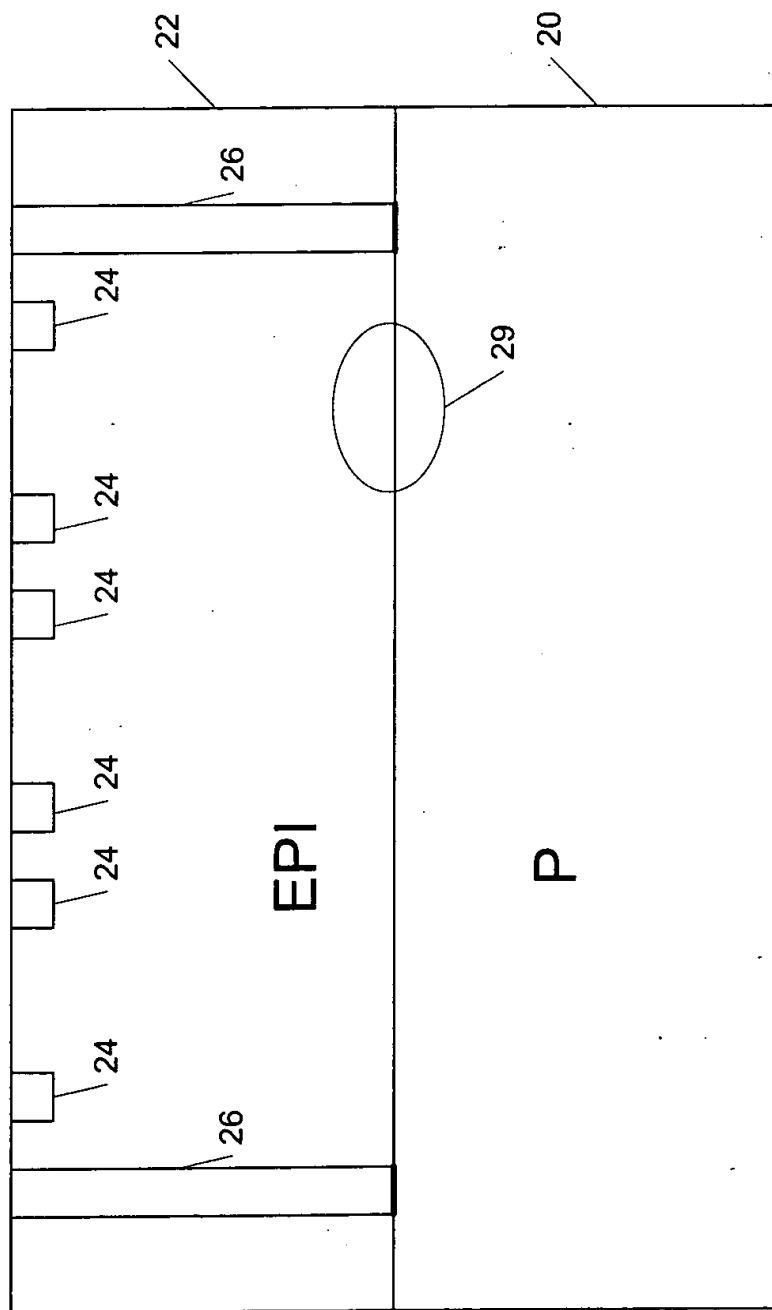


Fig. 2d

FIG. 2e is a cross-sectional view of a semiconductor device in accordance with the present invention. The device includes a substrate 20, an epitaxial layer 22, and a gate stack 24. The gate stack 24 is formed on the epitaxial layer 22 and includes a gate dielectric layer 26 and a gate electrode 27. The gate electrode 27 is formed on the gate dielectric layer 26 and is electrically connected to a source/drain region 28. The source/drain region 28 is formed in the epitaxial layer 22 and is electrically connected to the gate electrode 27. The device is formed on a substrate 20.

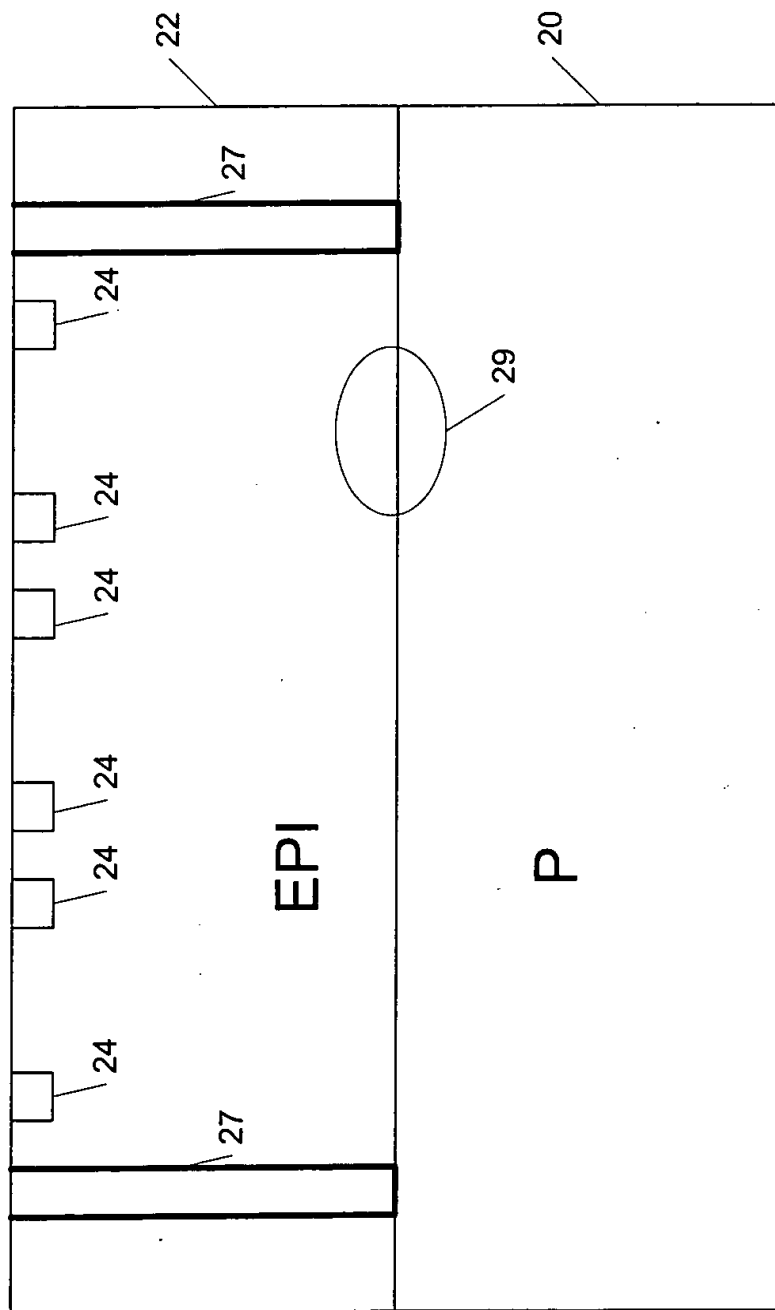


Fig. 2e

FIG. 2f is a cross-sectional view of a semiconductor device in accordance with the present invention. The device includes a substrate 20, an epitaxial layer 22, and a gate stack 24. The gate stack 24 is formed on the epitaxial layer 22 and includes a gate dielectric layer 28 and a gate electrode layer 29. The gate electrode layer 29 is formed on the gate dielectric layer 28 and is electrically connected to the epitaxial layer 22. The gate dielectric layer 28 is formed on the epitaxial layer 22 and is electrically insulated from the gate electrode layer 29. The gate electrode layer 29 is formed on the gate dielectric layer 28 and is electrically connected to the epitaxial layer 22. The gate dielectric layer 28 is formed on the epitaxial layer 22 and is electrically insulated from the gate electrode layer 29.

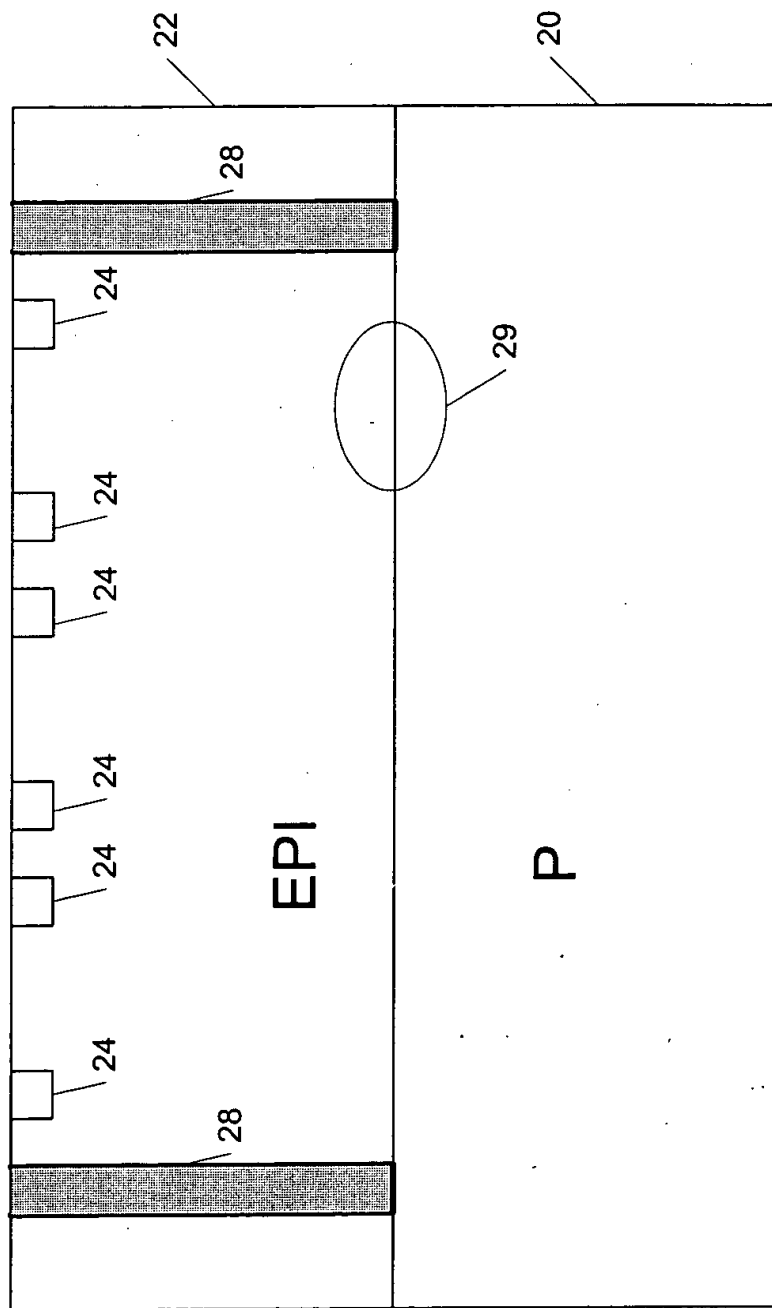


Fig. 2f

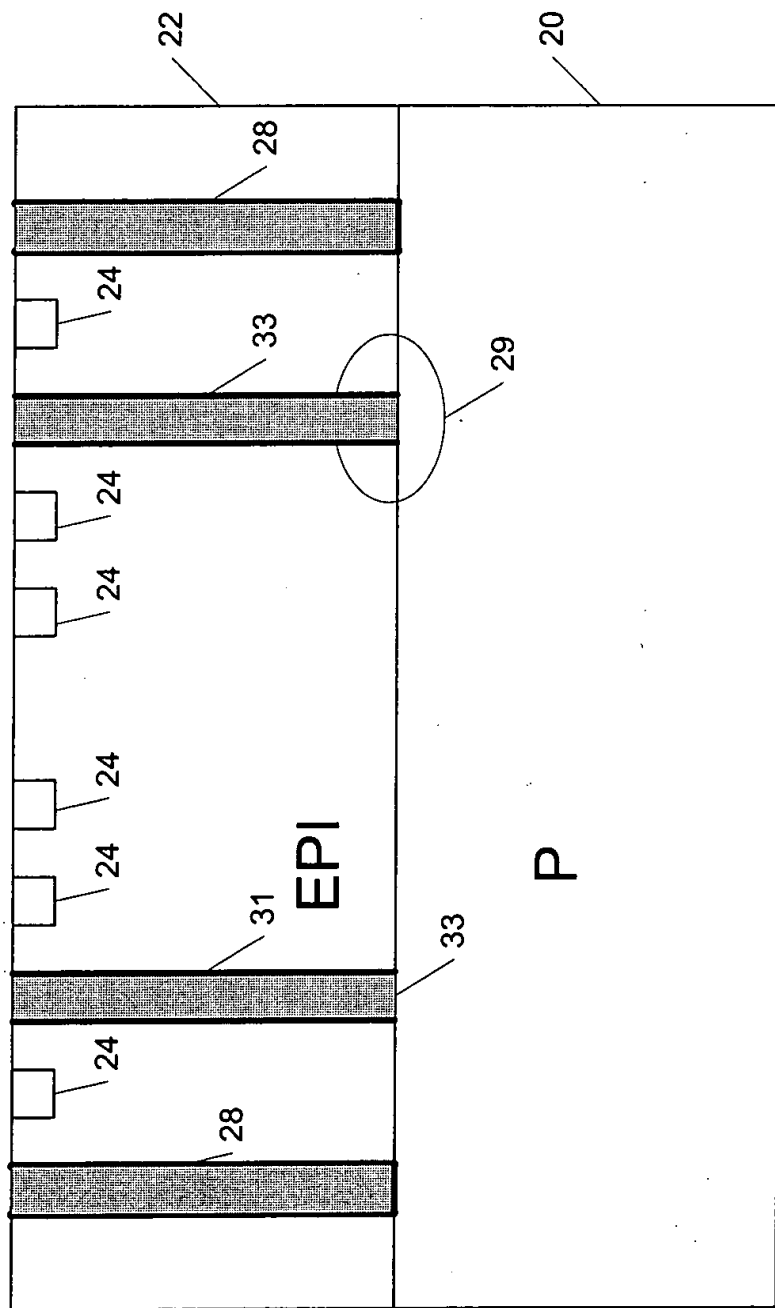


Fig. 29



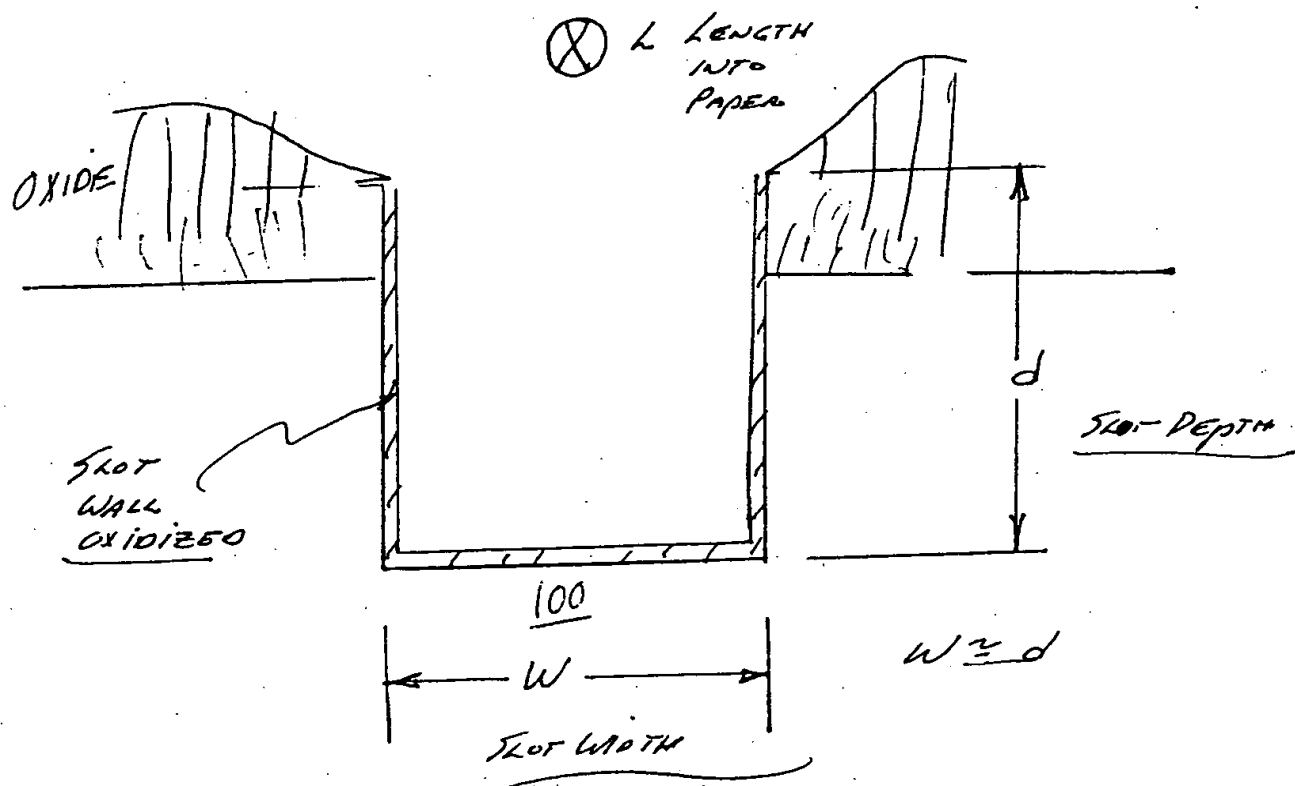


Fig. 3

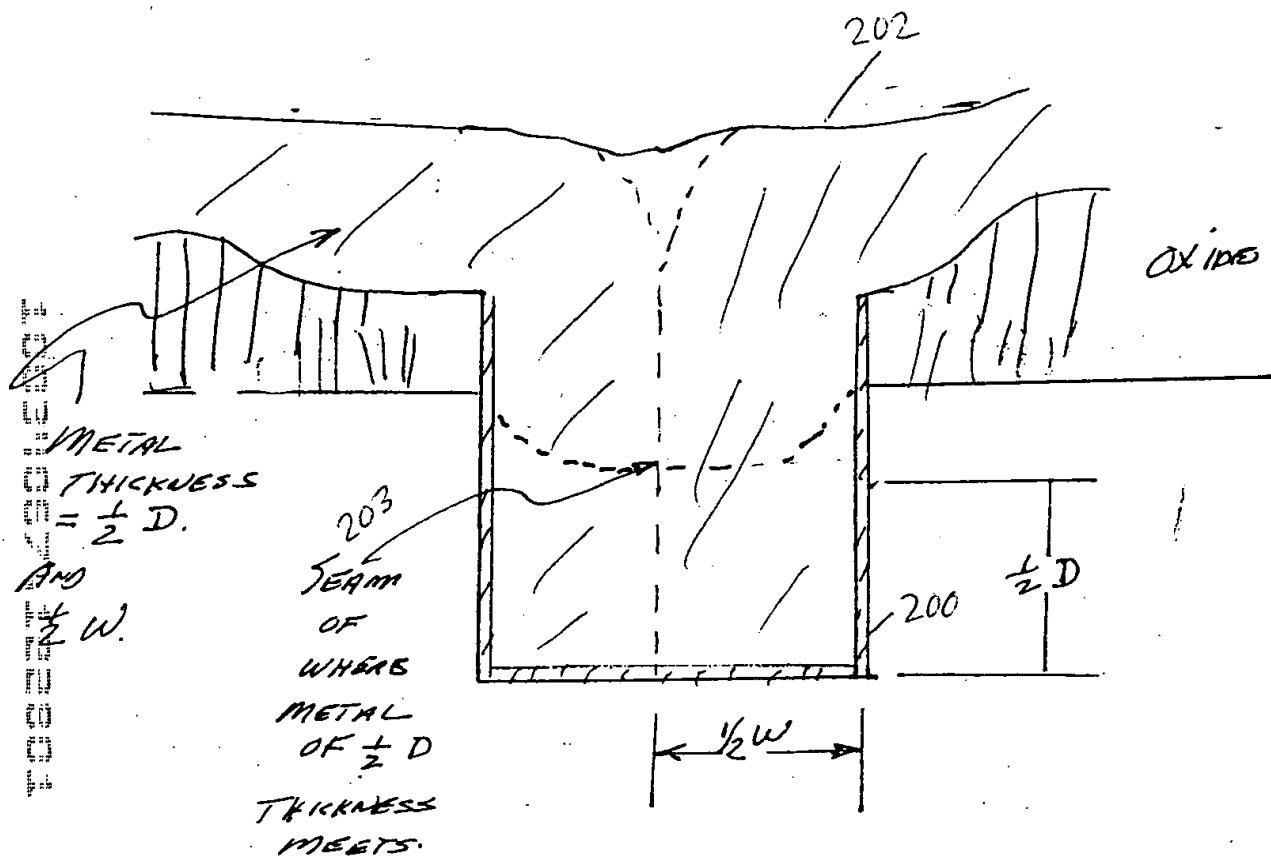
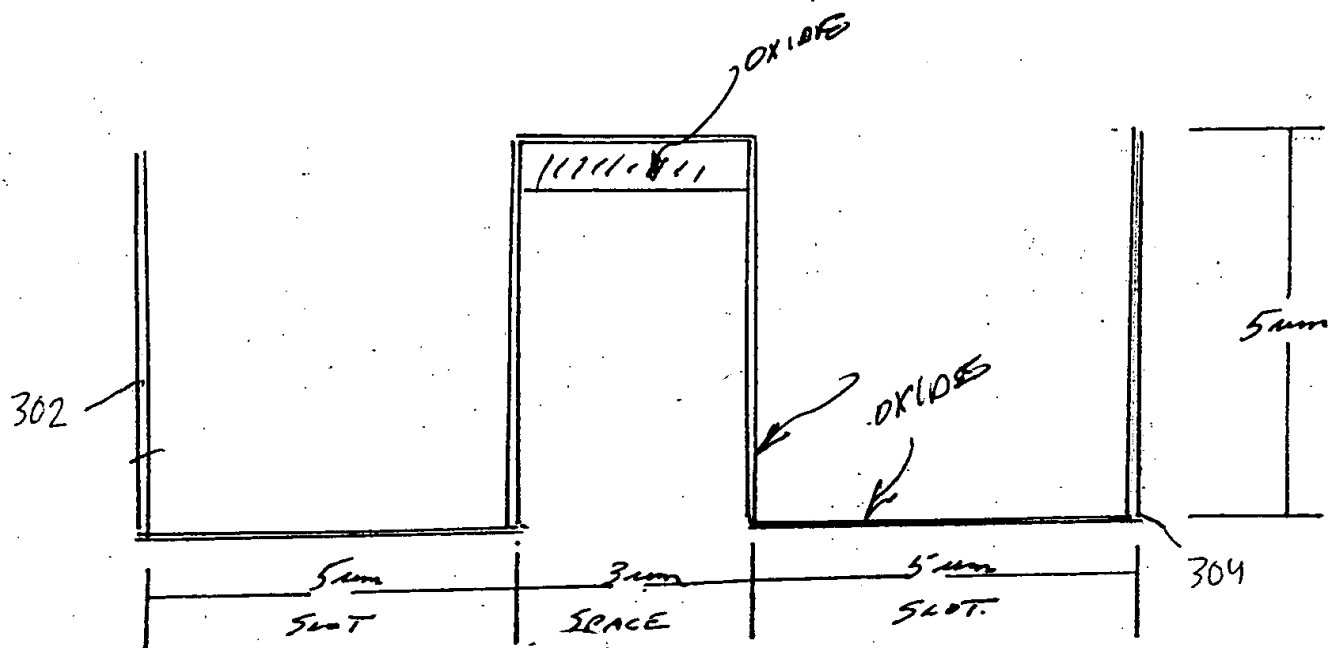
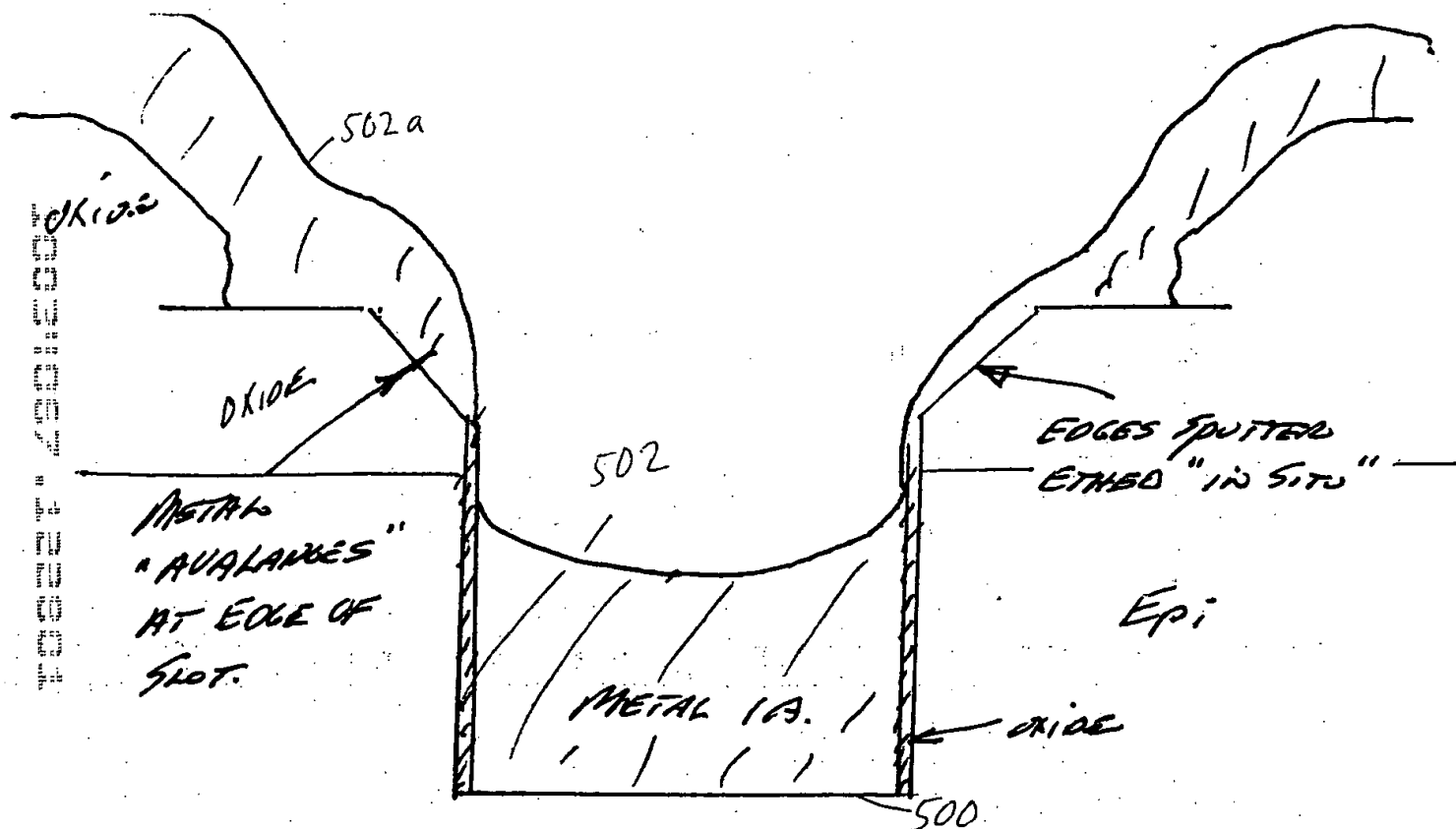


Fig. 4



DOUBLE SLOT FOR  
DOUBLE WIDTH OF METAL.  
3mm SPACE BETWEEN SLOTS

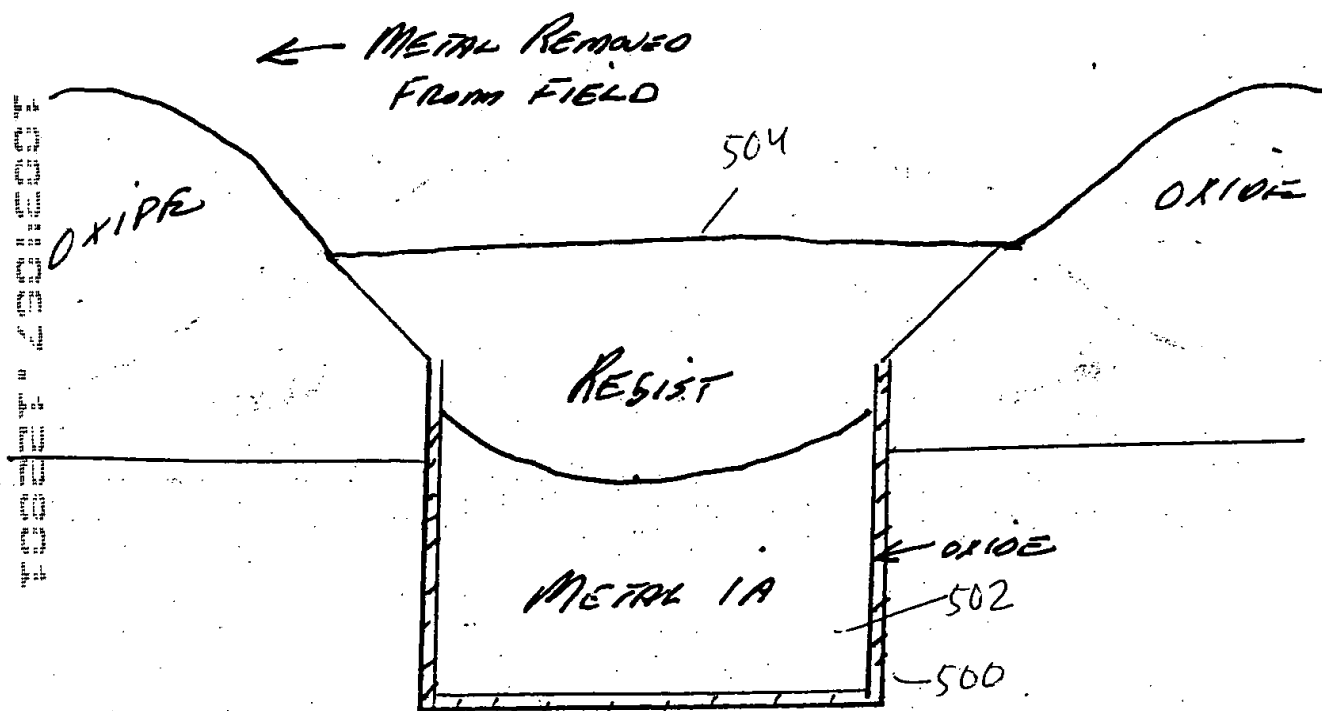
Fig. 4a



Prior TO METAL 1A BEING  
 SPUTTERED, THE EDGES OF THE OXIDES  
 ARE SPUTTERED ETCHED "IN SITU" &  
 1A DEPOSITED

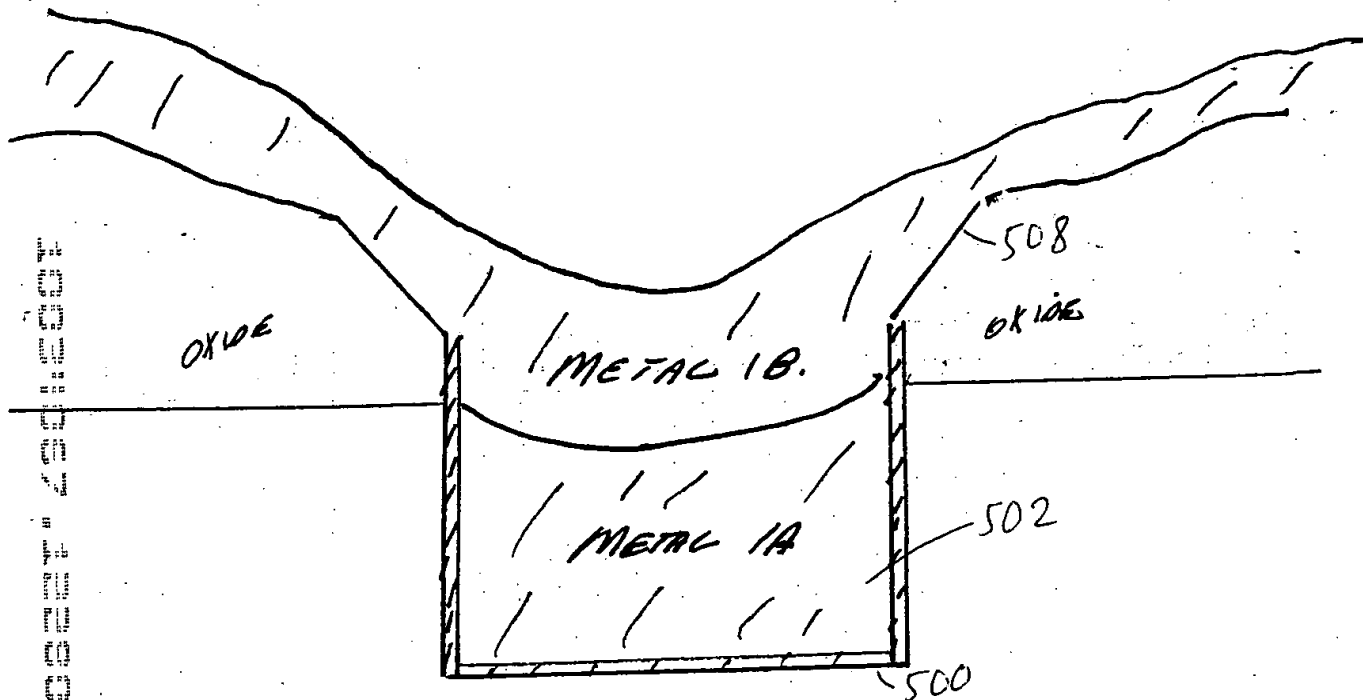
Fig. 5





RESIST PATTERN ETCHED.  
 LEAVING RESIST IN FLOTS  
 FIELD METAL ETCHED OFF.

Fig. 7



RESIST STRIPPED & SECOND  
METAL 1B SPUTTER DEPOSITED

Fig. 8

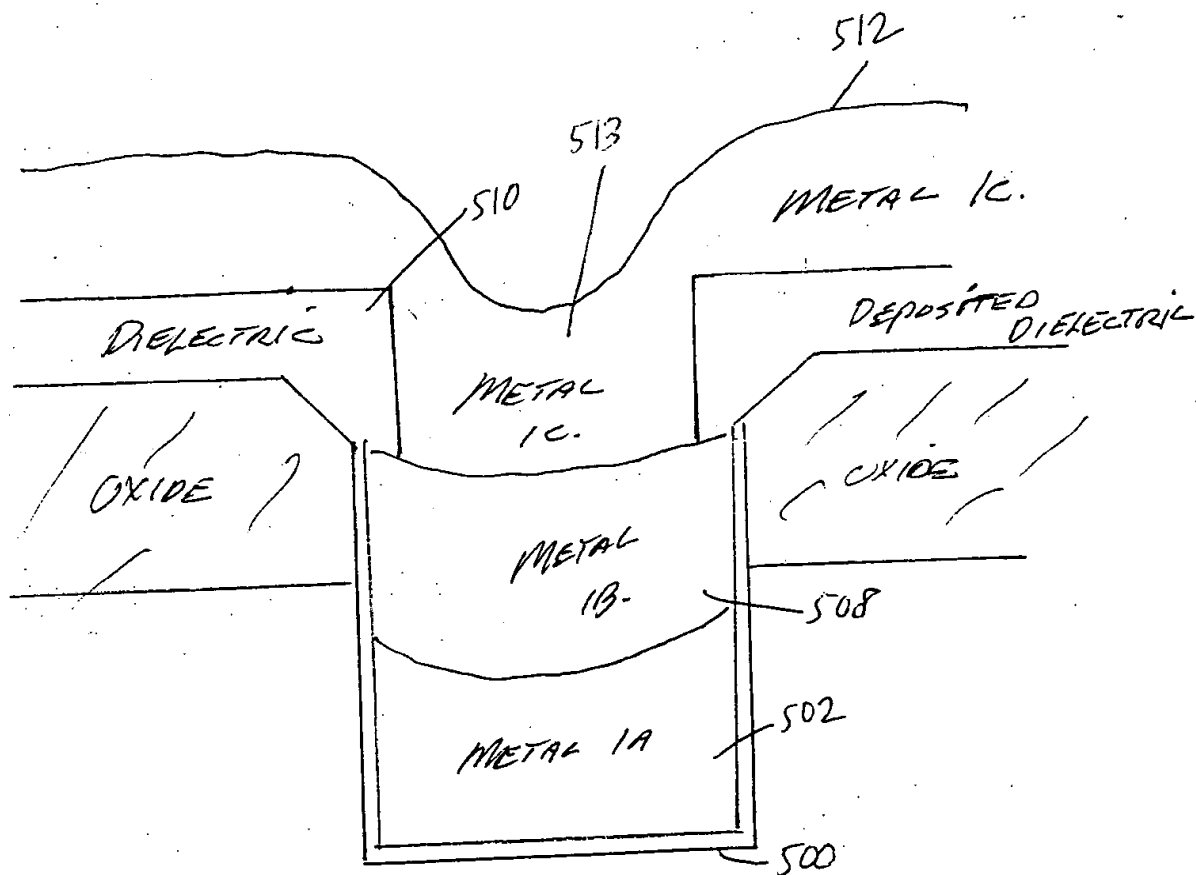


Fig. 9



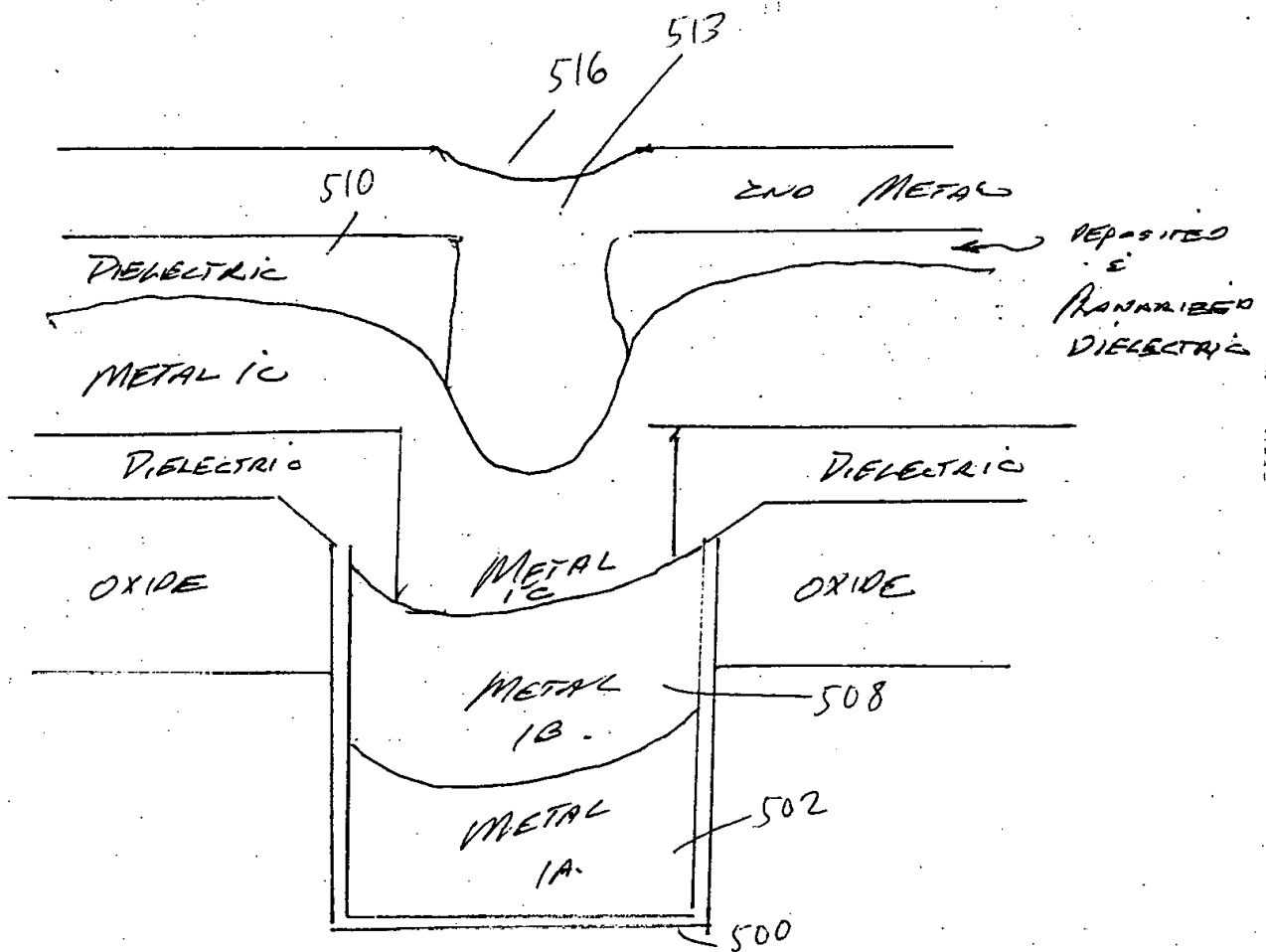
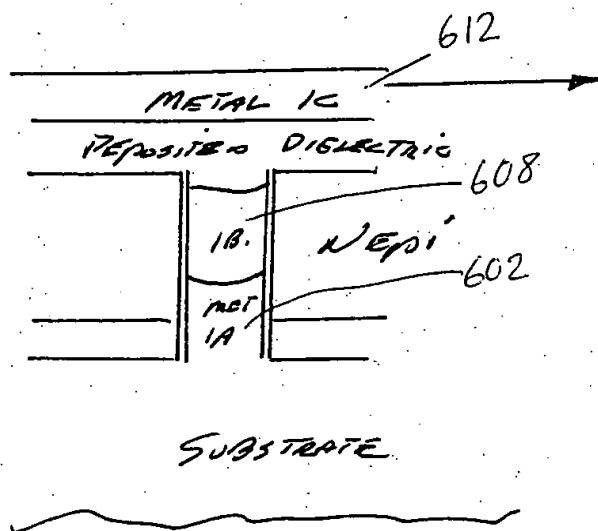


Fig. 10





METAL 1C  
 CONNECTS AN ISOLATED  
 ISLAND TO ADJACENT  
 ISOLATED EPI ISLANDS  
 AND CROSSES OVER THE  
 ISOLATION GROUND  
 STRAP BY NOT OPENING  
 A VIA IN THIS PORTION  
 TO ALLOW IC TO BE  
 ISOLATED FROM GROUND.

Fig. 12